Product/Process Change Notice - PCN 15_0121 Rev. -

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title: ADuM2200W/ADuM2201W Die Revision and Data Sheet Changes

Publication Date: 08-Oct-2015

Effectivity Date: 06-Jan-2016 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:

Initial Release

Description Of Change

Die Changes:
1. Increased pulse width of edge pulses and refresh pulses.
2. Increased separation between consecutive pulses on rising edge and refresh high pulses.
3. Additional layer of polyimide passivation on top of the non-coil die.

Data Sheet Changes:
1. Increased Idd-Dynamic current specifications. See data sheet specification comparison attachment for resulting values.
2. Changed Voh/Vol test conditions from Iox=-4mA/4mA to Iox=-3.2mA/3.2mA.

Reason For Change

Die Changes:
1. Ensure receiver can reliably detect all edge pulses and all refresh pulses.
2. Ensure 2nd pulse on rising edge or refresh high is consistently detected by receiver.
3. Polyimide offers the following advantages: improved ESD robustness, enhanced protection against die scratches, package stresses, surface ESD/EOS events and radiation.

Data Sheet Changes:
1. Increase in size of existing capacitors in receiver block caused increase in Idd-Dynamic current.
2. Express Voh/Vol levels with a load equal to the current required to drive two standard TTL gates.

Impact of the change (positive or negative) on fit, form, function & reliability

No change to fit, form, or reliability. Improved functional robustness.

Summary of Supporting Information

Qualification has been performed per AEC-Q100, Stress Test Qualification for Integrated Circuits. See attached Qualification Results Summary.

Supporting Documents

Attachment 1: Type: Qualification Results Summary

ADI_PCN_15_0121_Rev_-_ADuM220xW_SOIC_W_Qual_Results_Summary.pdf

Attachment 2: Type: Datasheet Specification Comparison

ADI_PCN_15_0121_Rev_-_ADUM2200_R2 IDD Data Sheet Comparison.pdf

Attachment 3: Type: Datasheet Specification Comparison

ADI_PCN_15_0121_Rev_-_ADUM2201_R2 IDD Data Sheet Comparison.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.					
Americas:	PCN_Americas@analog.com	**Europe:**	PCN_Europe@analog.com	**Japan:**	PCN_Japan@analog.com
				Rest of Asia:	PCN_ROA@analog.com

Appendix A - Affected ADI Models				
Added Parts On This Revision - Product Family / Model Number (8)				
ADUM2200 / ADUM2200WARWZ	ADUM2200 / ADUM2200WARWZ-RL	ADUM2200 / ADUM2200WBRWZ	ADUM2200 / ADUM2200WBRWZ-RL	ADUM2201 / ADUM2201WARWZ
ADUM2201 / ADUM2201WARWZ-RL	ADUM2201 / ADUM2201WBRWZ	ADUM2201 / ADUM2201WBRWZ-RL		

Appendix B - Revision History			
Rev	**Publish Date**	**Effectivity Date**	**Rev Description**
Rev. -	08-Oct-2015	06-Jan-2016	Initial Release